**IGBT MODULE** 

### MBM1000FS17G2-C

Silicon N-channel Side-gate HiGT 1700V G2 version with SiC Diode.

#### **FEATURES**

- \* Low power dissipation by side-gate HiGT.
- \* Ultra low recovery loss with SiC-SBD.
- \* Low noise & easy drive through low Cies and Cres
- \* High current density & half-bridge nHPD2 module with low stray inductance.
- \* Scalable large current easily handled by paralleling.
- \* Built in temperature sensor.

\* Equipped with current sensing terminals.

HiGT : High-conductivity IGBT nHPD<sup>2</sup> : next High Power Density Dual

#### ABSOLUTE MAXIMUM RATINGS (Tc=25°C)

ltem		Symbol	Unit	MBM1000FS17G2-C
Collector Emitter Voltage		$V_{\sf CES}$	V	1,700
Gate Emitter Voltage		$V_{GES}$	V	±20
Collector Current	DC	lc	- A	1,000
Collector Current	1ms	I <sub>CRM</sub>	_ ^	2,000
Forward Current	DC	I <sub>F</sub>	A	1,000
Forward Current	1ms	I <sub>FRM</sub>	^	2,000
Junction Temperature		T <sub>vj op</sub>	°C	-40 ~ +150
Storage Temperature		$T_{stg}$	°C	-40 ~ +150
Isolation Voltage		V <sub>ISO</sub>	V <sub>RMS</sub>	4,000(AC 1 minute)
Caracus Tarressa	Terminals (M3/M8)	-	N·m	0.8/15
Screw Torque	Mounting (M6)	-	111.111	6.0 (1)

Notes: (1) Recommended Value 5.5±0.5N·m

#### **ELECTRICAL CHARACTERISTICS**

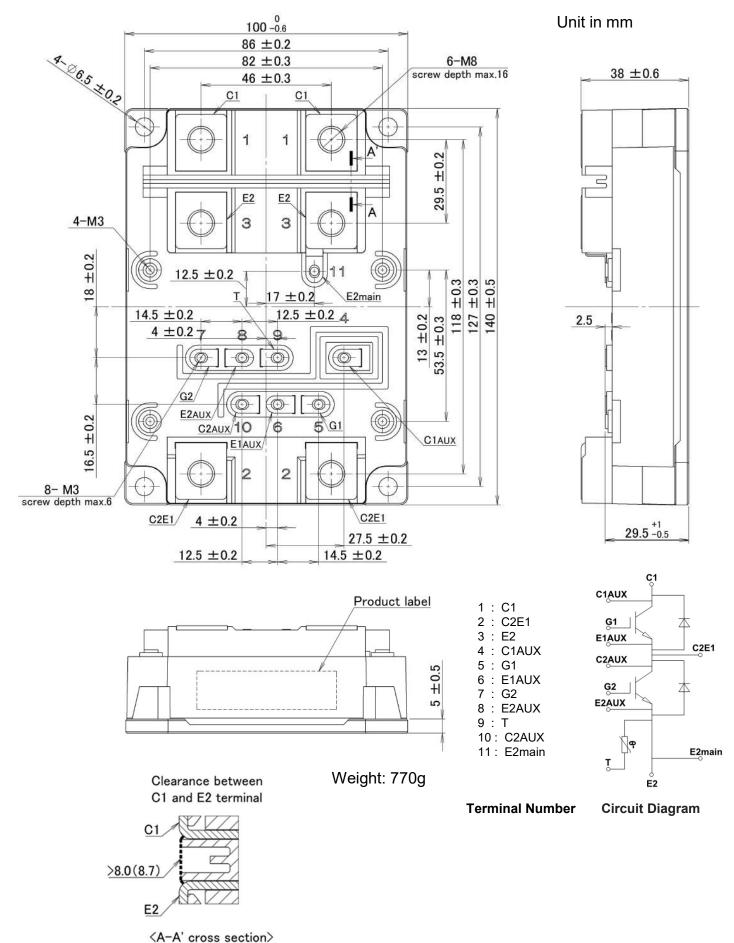
Item		Symbol	Unit	Min.	Тур.	Max.	Test Conditions
Collector Emitter Cut-	Off Current	I <sub>CES</sub>	mA	-	1	20	V <sub>CE</sub> =1,700V, V <sub>GE</sub> =0V, T <sub>vj</sub> =25°C
Concetor Emitter Out-On Guitent		ICES	111/	-	10	-	$V_{CE}$ =1,700V, $V_{GE}$ =0V, $T_{vj}$ =150°C
Gate Emitter Leakage	Current	I <sub>GES</sub>	nΑ	-500	-	+500	$V_{GE}=\pm 20V, V_{CE}=0V, T_{vj}=25^{\circ}C$
Collector Emitter Satu	ration Voltage	V <sub>CEsat</sub>	V	-	1.85	-	I <sub>C</sub> =1,000A, V <sub>GE</sub> =15V, T <sub>vj</sub> =25°C
	<u> </u>		<u> </u>	-	2.15	2.6	Ic=1,000A, V <sub>GE</sub> =15V, T <sub>vj</sub> =150°C
Gate Emitter Threshol	d Voltage	V <sub>GE(th)</sub>	V	6.0	7.0	8.0	V <sub>CE</sub> =10V, I <sub>C</sub> =1,000mA, T <sub>vj</sub> =25°C
Input Capacitance		C <sub>ies</sub>	nF	-	46	-	$V_{CE}$ =10V, $V_{GE}$ =0V, f=100kHz, $T_{vj}$ =25°C
Internal Gate Resistar	ice	R <sub>G(int)</sub>	Ω	-	6.8	-	V <sub>CE</sub> =10V, V <sub>GE</sub> =0V, f=100kHz, T <sub>vj</sub> =25°C
Turn On Delay Time		t <sub>d(on)</sub>		-	0.68	-	V <sub>CC</sub> =900V, I <sub>C</sub> =1,000A
Rise Time		t <sub>r</sub>	μS	-	0.15	-	L <sub>S</sub> =40nH
Turn Off Delay Time		t <sub>d(off)</sub>	μδ	-	0.88	-	$R_G(\text{on/off})=1.8\Omega/6.8\Omega$ (2)
Fall Time		t <sub>f</sub>		-	0.60	-	$V_{GE}=\pm 15V$ , $T_{vj}=150^{\circ}C$
Peak Forward Voltage Drop		VF	V	-	1.8	-	$I_F=1,000A, V_{GE}=0V, T_{vj}=25^{\circ}C$
reak rolward voltage	: Біор	VF	V	-	2.7	3.6	I <sub>F</sub> =1,000A, V <sub>GE</sub> =0V, T <sub>Vi</sub> =150°C
Bayaraa Baaayary Tin	22	4	μS	-	0.06	-	V <sub>CC</sub> =900V, I <sub>F</sub> =1,000A, L <sub>S</sub> =40nH
Reverse Recovery Tin	ie	t <sub>rr</sub>					T <sub>vj</sub> =150°C
Turn On Loss		Eon	J/P	-	0.16	0.25	V <sub>CC</sub> =900V, I <sub>C</sub> =1,000A, L <sub>S</sub> =40nH
Turn Off Loss		E <sub>off</sub>	J/P	-	0.34	0.45	$R_G(\text{on/off})=1.8\Omega/6.8\Omega$ (2)
Reverse Recovery Los	SS	Err	J/P	-	0.01	-	$V_{GE}=\pm 15V, T_{vj}=150^{\circ}C$
							V <sub>CC</sub> =1,000V, Ls=40nH,
Short Circuit Pulse Wi	dth	t <sub>sc</sub>	μS	10	_	-   -	$R_G(\text{on/off})=1.8\Omega/82\Omega$ ,
			·				$V_{GF} = \pm 15 \text{ V}, T_{vi} = 150 ^{\circ}\text{ C}$
Stray inductance mod	ule	L <sub>SCE</sub>	nΗ	-	9	-	Between C1(main) and E2(main)
-	Resistance	R <sub>25</sub>	kΩ	-	5	-	Tc=25°C
NTC-Thermistor	Deviation	ΔR/R	%	-5	-	5	Tc=25°C
	B-constant	B <sub>(25/50)</sub>	K	-	3375	-	Between 25°C and 50°C
Thermal Impedance	IGBT	R <sub>th(j-c)</sub>	K/W	-	-	0.027	lunation to coop
Thermal Impedance	FWD	R <sub>th(j-c)</sub>	r\/vv	-	-	0.047	Junction to case
Contact Thermal Impe	dance	R <sub>th(c-f)</sub>	K/W	-	0.02	-	Case to fin (per 1 arm)

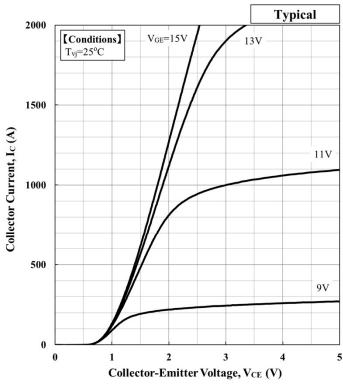
Notes: (2)  $R_G$  value is a test condition value for evaluation, not recommended value. Please, determine the suitable  $R_G$  value by measuring switching behaviors.

- \* Please contact our representatives at order.
- \* For improvement, specifications are subject to change without notice.
- \* For actual application, please confirm this spec sheet is the newest revision.
- \* ELECTRICAL CHARACTERISTIC items shown in above table are according to IEC 60747-2 and IEC 60747-9.



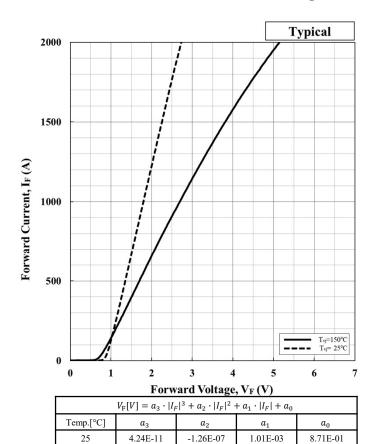
#### **OUTLINE DRAWING**





$V_{\text{CE}}(sat)[V] = a_3 \cdot  I_c ^3 + a_2 \cdot  I_c ^2 + a_1 \cdot  I_c  + a_0$							
Temp.[°C]	$V_{GE}[V]$	$a_3$	$a_2$	$a_1$	$a_0$		
25	15	1.35E-10	-5.28E-07	1.38E-03	8.21E-01		

Collector Current vs. Collector Emitter Voltage



Forward Voltage of free-wheeling diode

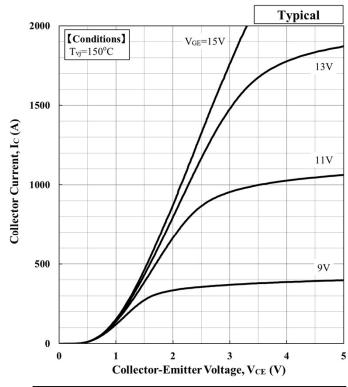
-1.79E-07

2.02E-03

7.15E-01

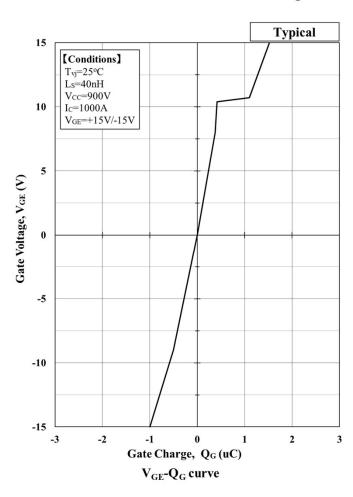
1.39E-10

150

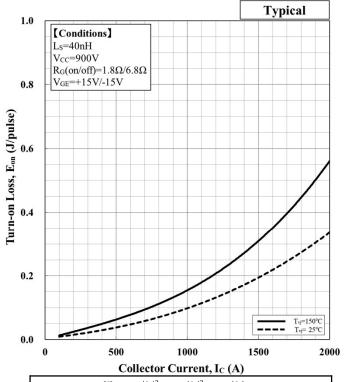


$V_{\text{CE}}(sat)[V] = a_3 \cdot  I_c ^3 + a_2 \cdot  I_c ^2 + a_1 \cdot  I_c  + a_0$							
Temp.[°C] $V_{GE}[V]$ $a_3$ $a_2$ $a_1$ $a_0$							
150	15	2.20E-10	-8.10E-07	2.05E-03	6.93E-01		

Collector Current vs. Collector Emitter Voltage

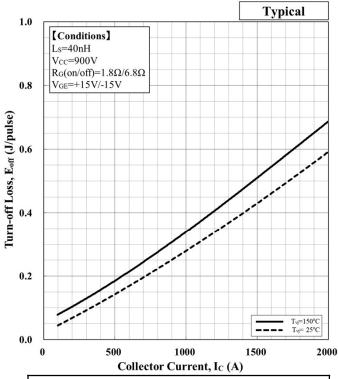






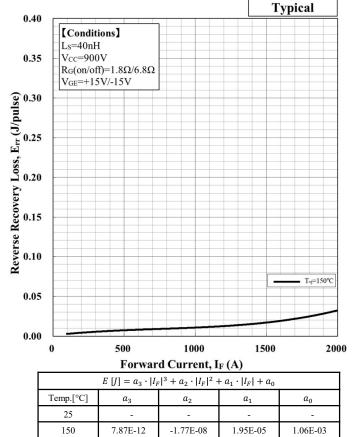
	, - ( )							
	$E\left[J\right] = a_3 \cdot  I_c ^3 + a_2 \cdot  I_c ^2 + a_1 \cdot  I_c  + a_0$							
Temp.[°C] $a_3$ $a_2$ $a_1$ $a_0$								
	25	1.30E-11	3.33E-08	4.77E-05	4.28E-03			
	150	4.41E-11	-5.53E-09	1.14E-04	1.79E-03			

Turn-on loss vs. Collector current



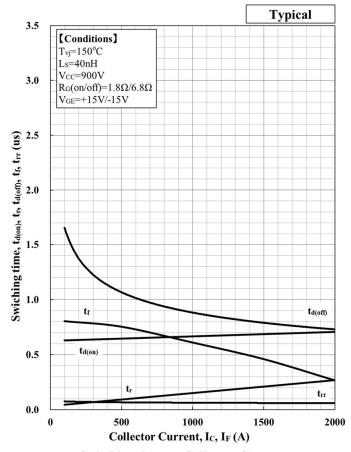
$E[J] = a_3 \cdot  I_c ^3 + a_2 \cdot  I_c ^2 + a_1 \cdot  I_c  + a_0$							
Temp.[ $^{\circ}$ C] $a_3$ $a_2$ $a_1$ $a_0$							
25	-3.46E-12	3.77E-08	2.23E-04	2.22E-02			
150	-1.24E-11	6.91E-08	2.27E-04	5.57E-02			

Turn-off loss vs. Collector current



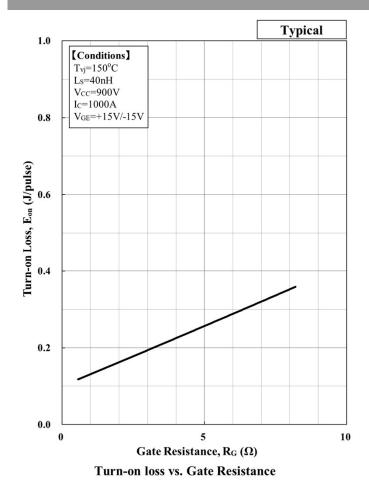
7.87E-12 -1.77E-08 1.95E-05

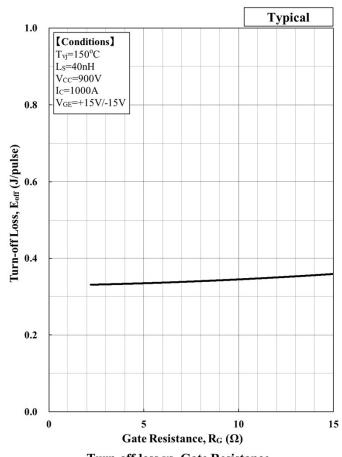
Recovery loss vs. Forward current

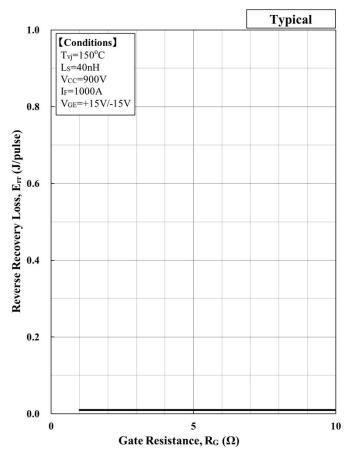


Switching time vs. Collector Current





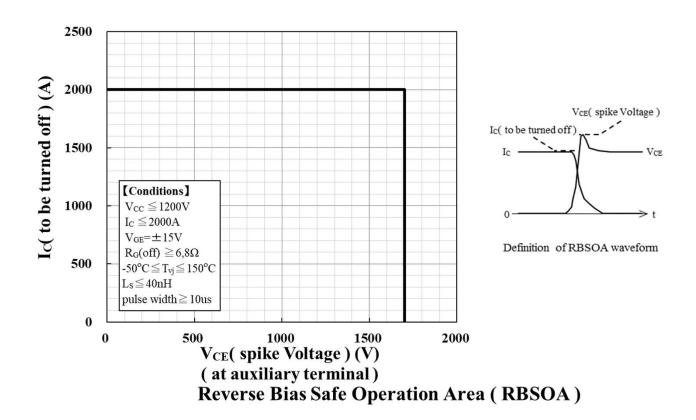




Reverse Recovery loss vs. Gate Resistance

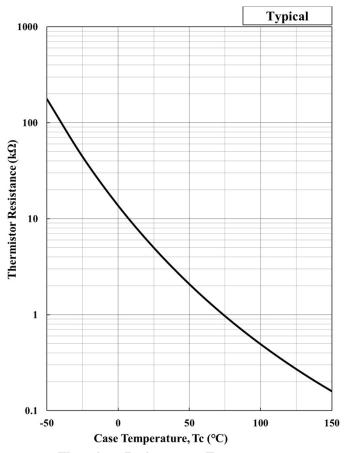
Turn-off loss vs. Gate Resistance



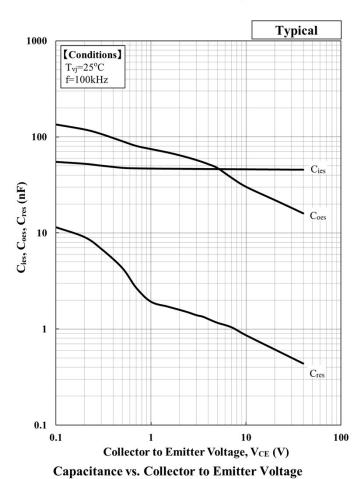


**IGBT MODULE** 

# MBM1000FS17G2-C



Thermistor Resistance vs. Temperature



0.1 Diode

| Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | Diode | D

**Transient Thermal Ipedance Curve** 

Foster model lumped circuit constant

n	1	2	3	4	Unit
R th, IGBT [n]	4.22E-03	6.22E-03	1.30E-02	3.70E-03	[K/W]
C th, IGBT [n]	4.93E+02	3.20E+01	2.43E+00	4.06E-01	[J/K]
R th, Diode [n]	6.48E-03	1.19E-02	2.18E-02	7.43E-03	[K/W]
C th, Diode [n]	3.21E+02	1.68E+01	1.45E+00	2.02E-01	[J/K]

#### Cauer model lumped circuit constant

n	1	2	3	4	Unit
R th, IGBT [n]	5.11E-03	1.37E-02	5.05E-03	3.32E-03	[K/W]
C th, IGBT [n]	3.44E-01	2.12E+00	3.97E+01	5.80E+02	[J/K]
R th, Diode [n]	9.79E-03	2.33E-02	9.32E-03	5.09E-03	[K/W]
C th, Diode [n]	1.75E-01	1.28E+00	2.10E+01	3.83E+02	[J/K]



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- 3. Semiconductor devices may sometimes break down by accidental or unexpected surge voltage, so please be careful about the safety design such as redundant design and malfunction prevention design which don't cause the damage expand even if they break down.
- 4. In cases where extremely high reliability is required (such as use in nuclear power control, aerospace and aviation, traffic equipment, life-support-related medical equipment, fuel control equipment and various kinds of safety equipment), safety should be ensured by using semiconductor devices that feature assured safety or by means of users' fail-safe precautions or other arrangement. Or consult with Hitachi's sales department staff. (When semiconductor devices fail, as a result the semiconductor devices or wiring, wiring pattern may smoke, ignite, or the semiconductor devices themselves may burst.)
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- 6. This specification is a material for component selection, which describes specifications of power semiconductor devices (hereinafter referred to as products), characteristic charts, and external dimension drawings.
- 7. The information given herein, including the specifications and dimensions, is subject to change without prior notice to improve product characteristics. Before ordering, purchasers are advised to contact with Hitachi power semiconductor sales department for the latest version of this data sheets.
- 8. For handling other than described in this manual, follow the handling instructions (IGBT-HI-00002).
- 9. In this module, the maximum depth of the screw holes on the main terminals is 16mm. Using screws longer than 16mm will break the case.

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